An Accurate Broad-Band Measurement of Substrate Dielectric Constant (Correction)

M.-Q. Lee and S. Nam. "An Accurate Broad-Band Measurement of Substrate Dielectric Constant (Correction)." 1996 Microwave and Guided Wave Letters 6.8 (Aug. 1996 [MGWL]): 299-299.

Since the connector shown in our letter is generally reciprocal, the determinant of the chain matrix of measurements is unity.

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